

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Min-hwa Chi

Serial No. not yet assigned

Filed: 5/24/01

For: TRANSISTOR AND LOGIC CIRCUIT  
ON THIN SILICON-ON-INSULATOR WAFERS  
BASED ON GATE INDUCED DRAIN  
LEAKAGE CURRENTS

Examiner: D. Kang

Art Unit: 2811

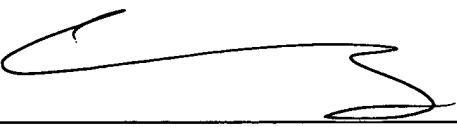
*# 2/Re. Amst A  
Aug 8/201*Assistant Commissioner for Patents  
Washington, DC 20231PRELIMINARY AMENDMENT

Sir or Madam:

Prior to examination of the above referenced application, Applicant  
respectfully request the Examiner to cancel Claims 1-10 and 19-26.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR and ZAFMAN

Dated: 5/24/01  
\_\_\_\_\_  
Chun M. Ng  
Reg. No. 36,878